


<b>Search Notes</b>  	<b>Application/Control No.</b>  10509616	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAHASHI ET AL.
	<b>Examiner</b>  Alain L Bashore	<b>Art Unit</b>  1792

SEARCHED			
Class	Subclass	Date	Examiner
427	127, 128, 131, 132	3-27-08	ab

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (attached)	3-27-08	ab
Inventor and assignee search	3-27-08	ab

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner